**Product specification** 

# FDG1024NZ

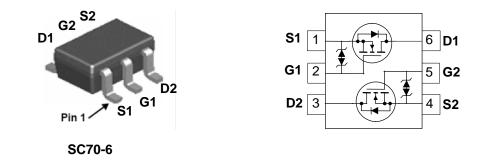
## TY Semicondutor<sup>®</sup>



### Features

- Max  $r_{DS(on)}$  = 175 m $\Omega$  at V<sub>GS</sub> = 4.5 V, I<sub>D</sub> = 1.2 A
- Max  $r_{DS(on)}$  = 215 m $\Omega$  at V<sub>GS</sub> = 2.5 V, I<sub>D</sub> = 1.0 A
- Max  $r_{DS(on)}$  = 270 m $\Omega$  at V<sub>GS</sub> = 1.8 V, I<sub>D</sub> = 0.9 A
- Max r<sub>DS(on)</sub> = 389 mΩ at V<sub>GS</sub> = 1.5 V, I<sub>D</sub> = 0.8 A
- HBM ESD protection level >2 kV (Note 3)
- Very low level gate drive requirements allowing operation in 3 V circuits (V<sub>GS(th)</sub> < 1.5 V)</p>
- Very small package outline SC70-6
- RoHS Compliant





## MOSFET Maximum Ratings T<sub>A</sub> = 25 °C unless otherwise noted

Symbol	Parameter			Ratings	Units	
V <sub>DS</sub>	Drain to Source Voltage			20	V	
V <sub>GS</sub>	Gate to Source Voltage			±8	V	
1	-Continuous	$T_A = 25^{\circ}C$	(Note 1a)	1.2	٨	
D	-Pulsed			6	— A	
D	Power Dissipation	$T_A = 25^{\circ}C$	(Note 1a)	0.36	10/	
P <sub>D</sub>	Power Dissipation	$T_A = 25^{\circ}C$	(Note 1b)	0.30	W	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range			-55 to +150	°C	

#### **Thermal Characteristics**

$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	350	°C/W
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	415	C/VV

### Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
.24	FDG1024NZ	SC70-6	7 "	8 mm	3000 units



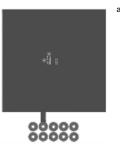
**Product specification** 



Symbol	Parameter	Test Conditions	Min	Тур	Max	Units	
Off Chara	acteristics						
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	I <sub>D</sub> = 250 μA, V <sub>GS</sub> = 0 V	20			V	
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, referenced to 25 °C		14		mV/°C	
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 16 V, V_{GS} = 0 V$			1	μΑ	
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 8 V, V_{DS} = 0 V$			±10	μΑ	
On Chara	octeristics						
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \ \mu A$	0.4	0.8	1.0	V	
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, referenced to 25 °C		-3		mV/°C	
-		$V_{GS} = 4.5 \text{ V}, \ I_D = 1.2 \text{ A}$		160	175		
		$V_{GS} = 2.5 \text{ V}, I_D = 1.0 \text{ A}$		185	215	mΩ	
r	Static Drain to Source On Resistance	$V_{GS} = 1.8 \text{ V}, \ I_D = 0.9 \text{ A}$		232	270		
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 1.5 \text{ V}, \ I_D = 0.8 \text{ A}$		321	389		
		V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 1.2 A, T <sub>J</sub> =125 °C		220	259		
9 <sub>FS</sub>	Forward Transconductance	V <sub>DD</sub> = 5 V, I <sub>D</sub> = 1.2 A		4		S	
Dynamic	Characteristics						
C <sub>iss</sub>	Input Capacitance			115	150	pF	
C <sub>oss</sub>	Output Capacitance	──V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, ──f = 1 MHz		25	35	pF	
C <sub>rss</sub>	Reverse Transfer Capacitance			20	25	pF	
R <sub>g</sub>	Gate Resistance			4.6		Ω	
Switching	g Characteristics						
t <sub>d(on)</sub>	Turn-On Delay Time			3.7	10	ns	
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 10 V, I <sub>D</sub> = 1.2 A,		1.7	10	ns	
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 4.5 \text{ V}, \text{ R}_{GEN} = 6 \Omega$		11	19	ns	
t <sub>f</sub>	Fall Time			1.5	10	ns	
Q <sub>g</sub>	Total Gate Charge	V 45.4.4 40.4		1.8	2.6	nC	
Q <sub>qs</sub>	Gate to Source Charge	— V <sub>GS</sub> = 4.5 V, V <sub>DD</sub> = 10 V, — I <sub>D</sub> = 1.2 A		0.3		nC	
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	-1D = 1.2  A		0.4		nC	
•	urce Diode Characteristics						
I <sub>S</sub>	Maximum Continuous Drain-Source Diode	Forward Current			0.3	Α	
V <sub>SD</sub>	Source to Drain Diode Forward Voltage	$V_{GS} = 0 V, I_S = 0.3 A$ (Note 2)		0.7	1.2	V	
50				1		L	

V <sub>SD</sub>	Source to Drain Diode Forward Voltage	$V_{GS} = 0 V, I_S = 0.3 A$ (Note 2)	0.7	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	− I <sub>F</sub> = 1.2 A, di/dt = 100 A/μs	10	20	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$-1_{\rm F} = 1.2$ A, di/dt = 100 A/µs	1.9	10	nC
NOTES:					

1.  $R_{0,IA}$  is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material.  $R_{0,IC}$  is guaranteed by design while  $R_{0,IA}$  is determined by the user's board design.



a. 350 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.

b. 415 °C/W when mounted on a minimum pad of 2 oz copper.

Pulse Test: Pulse Width < 300 μs, Duty cycle < 2.0%.</li>
The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.